

February 2010 SuperFET<sup>™</sup> FCH35N60 N-Channel MOSFET

# FCH35N60 600V N-Channel MOSFET

## Features

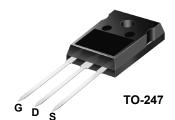
- 650V @ T<sub>J</sub> = 150°C
- Typ.R<sub>DS(on)</sub> = 0.079Ω
- Ultra low gate charge ( Typ. Q<sub>g</sub> = 139nC )
- Low effective output capacitance (Typ. C<sub>oss</sub>.eff = 340pF )
- 100% avalanche tested

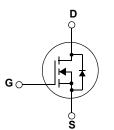


## Description

SuperFET<sup>TM</sup> is Farichild's proprietary, new generation of high voltage MOSFET family that is utilizing an advanced charge balance mechanism for outstanding low on-resistance and lower gate charge performance.

This advanced technology has been tailored to minimize conduction loss, provide superior switching performance, and withstand extreme dv/dt rate and higher avalanche energy. Consequently, SuperFET is very suitable for various AC/DC power conversion in switching mode operation for system miniaturization and higher efficiency.





## MOSFET Maximum Ratings T<sub>C</sub> = 25°C unless otherwise noted\*

	Ratings	Units			
Drain to Source Voltage	600	V			
Gate-Soure voltage	±30	V			
Droin Current	-Continuous (T <sub>C</sub> = 25 <sup>o</sup> C)		35		
DrainCurrent	-Continuous ( $T_C = 100^{\circ}C$ )		22.2	Α	
Drain Current	- Pulsed	- Pulsed (Note 1)		А	
Single Pulsed Avalanche Energy (N			1455	mJ	
Avalanche Current		(Note 1)	35	A	
Repetitive Avalanche Energy		(Note 1)	31.25	mJ	
Peak Diode Recovery dv/dt		(Note 3)	20	V/ns	
Dower Dissinction	(T <sub>C</sub> = 25°C)		312.5	W	
Power Dissipation	- Derate above 25°C		2.5	W/ºC	
Operating and Storage Temperature Range			-55 to +150	°C	
Maximum Lead Temperature for Soldering Purpose, 1/8" from Case for 5 Seconds			300	°C	
	Gate-Soure voltage         Gate-Soure voltage         Drain Current         Dirain Current         Single Pulsed Avalanche Err         Avalanche Current         Repetitive Avalanche Energ         Peak Diode Recovery dv/dt         Power Dissipation         Operating and Storage Tem         Maximum Lead Temperature	Gate-Soure voltage       -Continuous ( $T_C = 25^{\circ}C$ )         Drain Current       -Continuous ( $T_C = 100^{\circ}C$ )         Drain Current       - Pulsed         Single Pulsed Avalanche Energy         Avalanche Current         Repetitive Avalanche Energy         Peak Diode Recovery dv/dt         Power Dissipation         ( $T_C = 25^{\circ}C$ )         Operating and Storage Temperature Range         Maximum Lead Temperature for Soldering Purpose,	$ \begin{array}{c c c c c c c c c c c c c c c c c c c $	$\begin{array}{c c c c c c c c c c c c c c c c c c c $	

## **Thermal Characteristics**

Symbol	Parameter	Тур.	Max.	Units
$R_{ ext{ heta}JC}$	Thermal Resistance, Junction to Case	-	0.4	
$R_{\thetaCS}$	Thermal Resistance, Case-to-Heat Sink	0.24	-	°C/W
$R_{\thetaJA}$	Thermal Resistance, Junction to Ambient	-	42	

©2010 Fairchild Semiconductor Corporation FCH35N60 Rev. A1

1

Т
<b>O</b>
I
ω
()
Ζ
6
0
7
Ť.
0
5
b
3
Σ
e
$\leq$
0
õ
Ť
п
•

	Device Marking Device Pac		Packag	e l	Reel Size	Тар	e Width		Quantit	y
<u> </u>		TO-247	7	-	-	-		30		
- -	Chara	acteristics		I		- 1				
Symbol		Parameter		Tes	t Conditions		Min.	Тур.	Max.	Units
) Off Charac	toristics	•		1		1			1	
		•		L = 250 \		25 <sup>0</sup> C	600	-	-	V
BV <sub>DSS</sub> Drain to Source Breakdown Vol		age	age $\frac{I_{D} = 250 \mu A, V_{GS} = 0V, T_{J} = 25^{\circ}C}{I_{D} = 250 \mu A, V_{GS} = 0V, T_{J} = 150^{\circ}C}$			-	- 650	-	V	
ΔBV <sub>DSS</sub> ΔT <sub>1</sub>	Breakdo	reakdown Voltage Temperature		$I_D = 250\mu$ A, $V_{GS} = 0V$ , $I_J = 150^{\circ}$ C $I_D = 250\mu$ A, Referenced to $25^{\circ}$ C			_	0.6	-	V/°C
0		ource Avalanche Breako	lown							
3V <sub>DS</sub>	Voltage			$V_{GS} = 0V, I_D = 16A$			-	700	-	V
	Zoro Co	to Voltago Drain Curron	+	V <sub>DS</sub> = 600V, V <sub>GS</sub> = 0V			-	-	1	
DSS	288 Zero Gate Voltage Drain Current		ι	V <sub>DS</sub> = 480V,	Г <sub>С</sub> = 125 <sup>о</sup> С		-	-	10	μΑ
GSS	Gate to Body Leakage Current			$V_{GS}$ = ±30V,	V <sub>DS</sub> = 0V		-	-	±100	nA
On Charact	toristics									
	Gate Threshold Voltage			V <sub>GS</sub> = V <sub>DS</sub> , I	= 2504		3.0	-	5.0	V
V <sub>GS(th)</sub>		ain to Source On Resis	tanco				-	- 0.079	0.098	ν Ω
R <sub>DS(on)</sub>		Transconductance	lance	$V_{GS} = 10V, I_D = 17.5A$ $V_{DS} = 40V, I_D = 17.5A$				28.8	- 0.090	S S
9 <sub>FS</sub>				v <sub>DS</sub> - 400, i	- 11.3A		-	20.0	-	5
Dynamic C	haracte	ristics								
C <sub>iss</sub>	Input Ca	Capacitance It Capacitance		V <sub>DS</sub> = 25V, V <sub>GS</sub> = 0V f = 1MHz			-	4990	6640	pF
C <sub>oss</sub>	Output C						-	2380	3170	pF
C <sub>rss</sub>	Reverse	Transfer Capacitance					-	140	-	pF
C <sub>oss</sub>	Output Capacitance			V <sub>DS</sub> = 480V, V <sub>GS</sub> = 0V, f = 1.0MHz			-	113	-	pF
C <sub>oss</sub> eff.		Output Capacitance		$V_{DS}$ = 0V to 4	80V, V <sub>GS</sub> = 0	V	-	340	-	pF
ე <sub>g</sub>		te Charge at 10V			054		-	139	181	nC
ସୁ <sub>gs</sub>	Gate to S	Source Gate Charge		V <sub>DS</sub> = 480V, V <sub>GS</sub> = 10V	<sub>D</sub> = 35A	-	-	31	-	nC
Q <sub>gd</sub>	Gate to I	Drain "Miller" Charge		v <sub>GS</sub> = 10v		(Note 4)	-	69	-	nC
ESR	Equivale	nt Series Resistance (G	G-S)	Drain Open, F= 1MHZ			-	1.4	-	Ω
Switching	Charact	eristics								
d(on)	1	Delay Time					-	34	78	ns
		Rise Time		V <sub>DD</sub> = 300V, I <sub>D</sub> = 35A			-	120	250	ns
r	Turn-Off	Delay Time		$R_{G} = 4.7\Omega$ (Note 4)			-	105	220	ns
		Fall Time					-	73	155	ns
d(off)	Turn-Off					, ,				
d(off) f		o Characteristica								
d(off) f Drain-Sour	ce Diod	e Characteristics		Farmard Curr					25	•
d(off) f <b>Drain-Sour</b> S	<b>ce Diod</b> Maximun	n Continuous Drain to S			ent		-	-	35	A
d(off) f <b>Drain-Sour</b> s sM	<b>ce Diod</b> Maximun Maximun	n Continuous Drain to S n Pulsed Drain to Sourc	e Diode For	ward Current			-	-	105	Α
<sup>d(off)</sup> f <b>Drain-Sour</b>	<b>ce Diod</b> Maximun Maximun Drain to	n Continuous Drain to S	e Diode For		= 35A					

FCH35N60 Rev. A1

\*Notes:

7

1. V<sub>DS</sub> = 20V

\*Notes: 1. V<sub>GS</sub> = 0V

2. 250µs Pulse Test

\*Note: I<sub>D</sub> = 35A

120

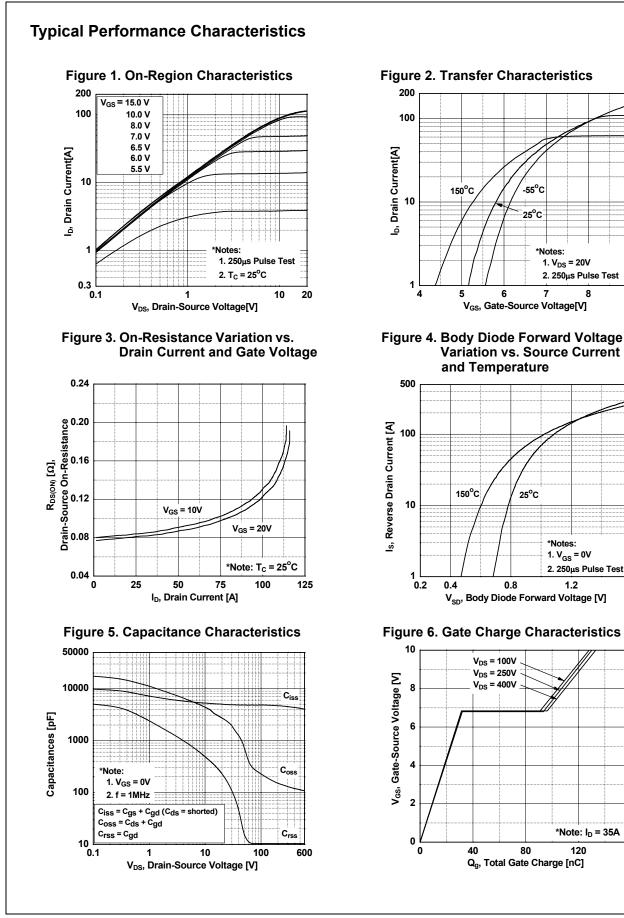
1.6

1.2

2. 250µs Pulse Test

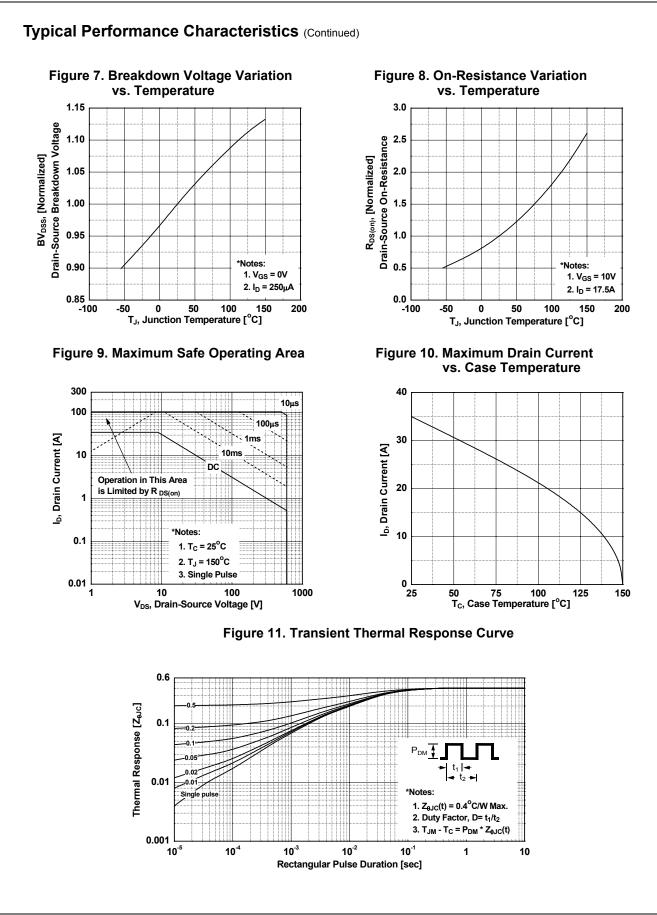
8

9



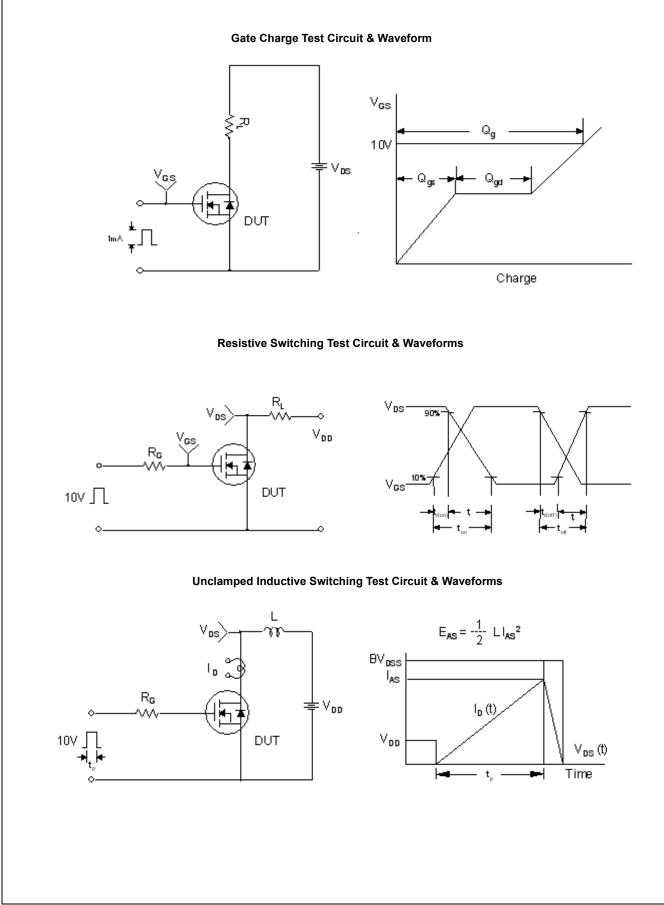
FCH35N60 Rev. A1

160

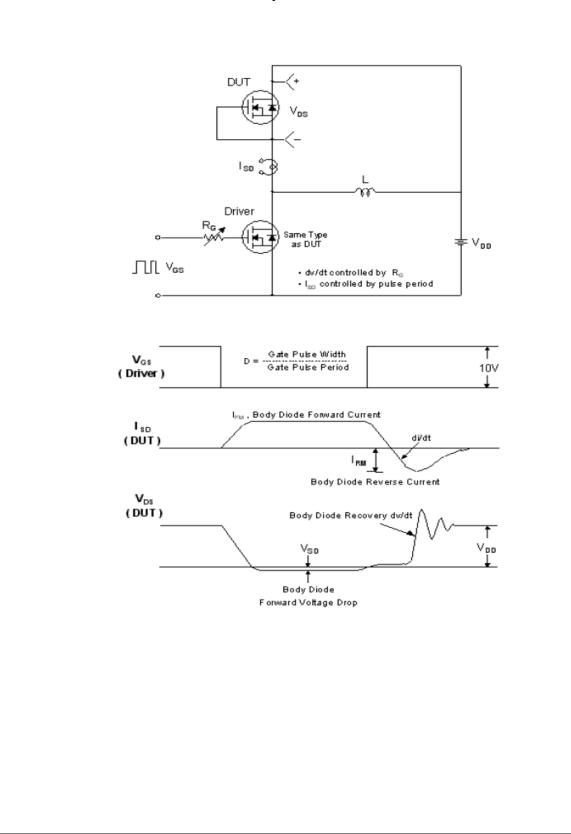


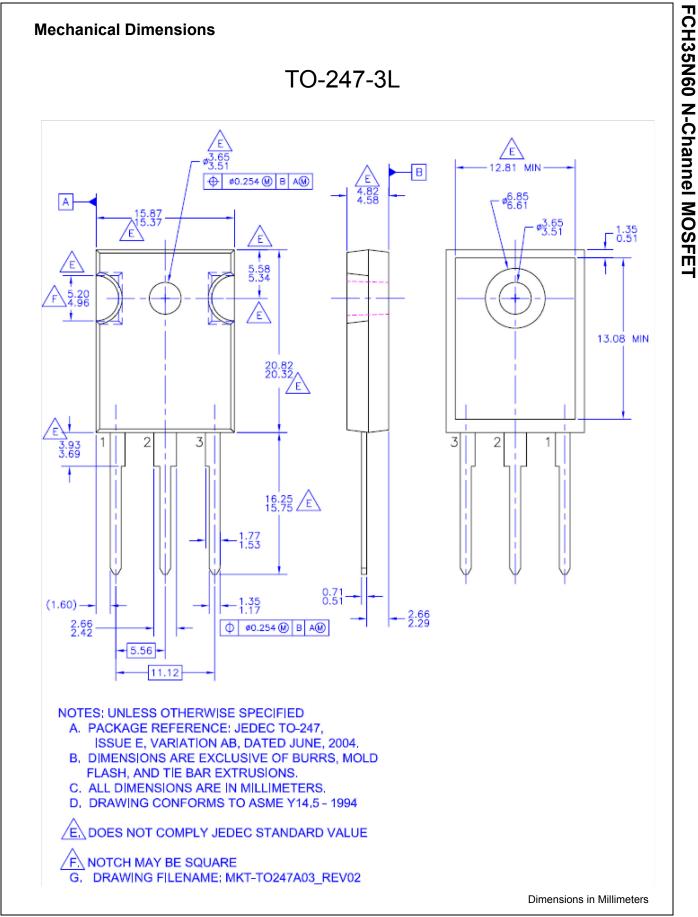
FCH35N60 Rev. A1

FCH35N60 N-Channel MOSFET



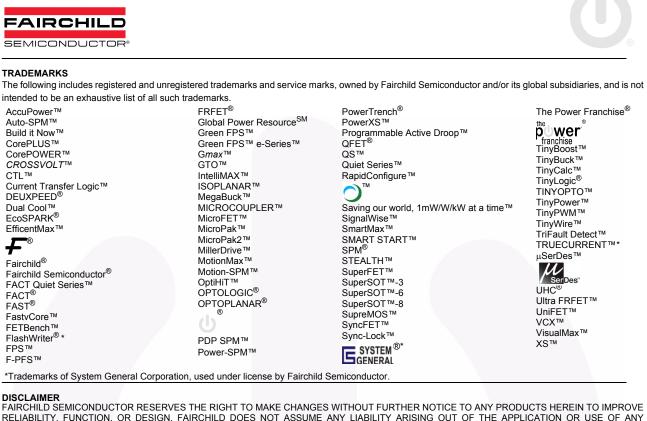
### Peak Diode Recovery dv/dt Test Circuit & Waveforms





FCH35N60 Rev. A1

7



FAIRCHILD SEMICONDUCTOR RESERVES THE RIGHT TO MAKE CHANGES WITHOUT FURTHER NOTICE TO ANY PRODUCTS HEREIN TO IMPROVE RELIABILITY, FUNCTION, OR DESIGN. FAIRCHILD DOES NOT ASSUME ANY LIABILITY ARISING OUT OF THE APPLICATION OR USE OF ANY PRODUCT OR CIRCUIT DESCRIBED HEREIN; NEITHER DOES IT CONVEY ANY LICENSE UNDER ITS PATENT RIGHTS, NOR THE RIGHTS OF OTHERS. THESE SPECIFICATIONS DO NOT EXPAND THE TERMS OF FAIRCHILD'S WORLDWIDE TERMS AND CONDITIONS, SPECIFICALLY THE WARRANTY THEREIN, WHICH COVERS THESE PRODUCTS.

LIFE SUPPORT POLICY FAIRCHILD'S PRODUCTS ARE NOT AUTHORIZED FOR USE AS CRITICAL COMPONENTS IN LIFE SUPPORT DEVICES OR SYSTEMS WITHOUT THE EXPRESS WRITTEN APPROVAL OF FAIRCHILD SEMICONDUCTOR CORPORATION.

#### As used herein:

- Life support devices or systems are devices or systems which, (a) are 1 intended for surgical implant into the body or (b) support or sustain life, and (c) whose failure to perform when properly used in accordance with instructions for use provided in the labeling, can be reasonably expected to result in a significant injury of the user.
- A critical component in any component of a life support, device, or 2. system whose failure to perform can be reasonably expected to cause the failure of the life support device or system, or to affect its safety or effectiveness.

#### ANTI-COUNTERFEITING POLICY

Fairchild Semiconductor Corporation's Anti-Counterfeiting Policy. Fairchild's Anti-Counterfeiting Policy is also stated on our external website, www.Fairchildsemi.com, under Sales Support.

Counterfeiting of semiconductor parts is a growing problem in the industry. All manufactures of semiconductor products are experiencing counterfeiting of their parts. Customers who inadvertently purchase counterfeit parts experience many problems such as loss of brand reputation, substandard performance, failed application, and increased cost of production and manufacturing delays. Fairchild is taking strong measures to protect ourselves and our customers from the proliferation of counterfeit parts. Fairchild strongly encourages customers to purchase Fairchild parts either directly from Fairchild or from Authorized Fairchild Distributors who are listed by country on our web page cited above. Products customers buy either from Fairchild directly or from Authorized Fairchild Distributors are genuine parts, have full traceability, meet Fairchild's quality standards for handing and storage and provide access to Fairchild's full range of up-to-date technical and product information. Fairchild and our Authorized Distributors will stand behind all warranties and will appropriately address and warranty coverage or other assistance for parts buying the part of the assistance for parts buying the formation and encourage our customers to do their part in stopping this practice by buying direct or from authorized distributors.

#### PRODUCT STATUS DEFINITIONS Definition of Terms

Datasheet Identification	Product Status	Definition
Advance Information	Formative / In Design	Datasheet contains the design specifications for product development. Specifications may change in any manner without notice.
Preliminary	First Production	Datasheet contains preliminary data; supplementary data will be published at a later date. Fairchild Semiconductor reserves the right to make changes at any time without notice to improve design.
No Identification Needed	Full Production	Datasheet contains final specifications. Fairchild Semiconductor reserves the right to make changes at any time without notice to improve the design.
Obsolete	Not In Production	Datasheet contains specifications on a product that is discontinued by Fairchild Semiconductor. The datasheet is for reference information only.

FCH35N60 Rev A1

8

FCH35N60 N-Channel MOSFE